Abstracts

Predictable Yield-Driven Circuit Optimization

J.W. Bandler, S. Ye, Q. Cai, R.M. Biernacki and S.H. Chen. "Predictable Yield-Driven Circuit Optimization." 1992 MTT-S International Microwave Symposium Digest 92.2 (1992 Vol. II [MWSYM]): 837-840.

This paper presents a comprehensive approach to predictable yield optimization. We utilize a new physics-based statistical GaAs MESFET model which combines the advantages of the dc Khatibzadeh and Trew model and the small-signal Ladbrooke formulas. The yield of a broadband amplifier is significantly improved after optimization. Predicted yield over a range of specifications is verified by device data. The benefits of simultaneous circuit-device yield optimization assisted by yield sensitivity analysis are demonstrated.

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